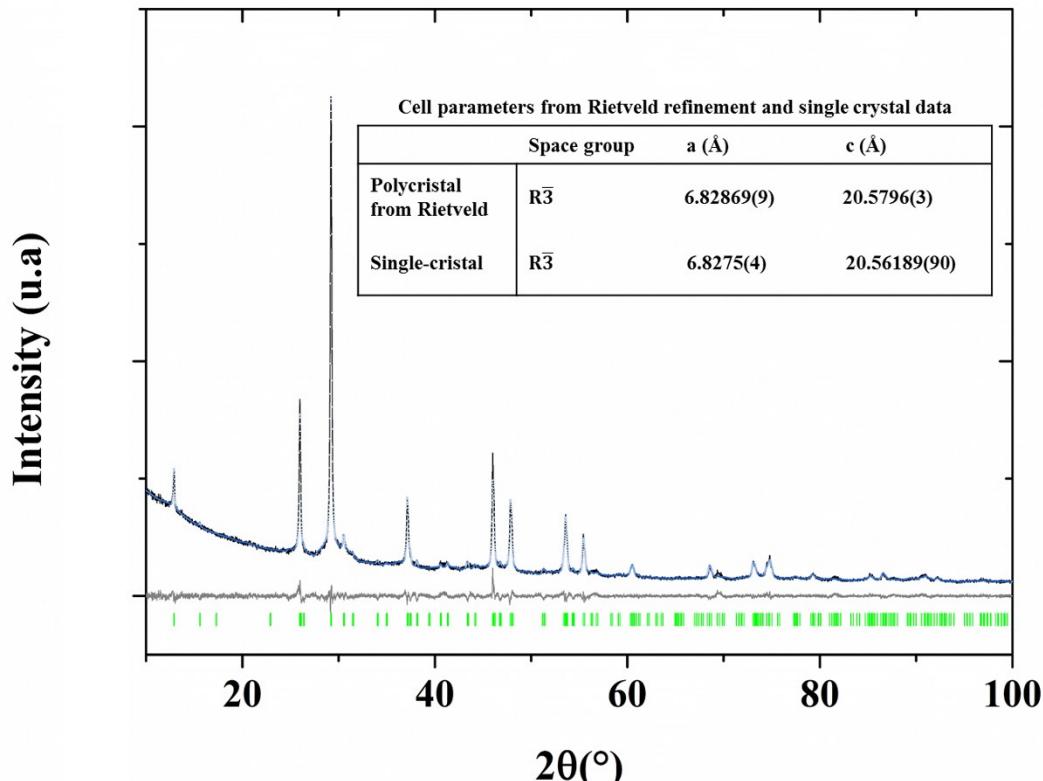


SFig.1



SFigure 1. Rietveld refinement plot for polycrystalline $\text{Cr}_2\text{Ge}_2\text{Te}_6$. Plot is represented as follows: observed (black line), calculated (blue dot), and difference (grey line) intensities. Bragg positions are indicated by green vertical bars. The included table shows the correspondence between the parameters of single-crystal characterization¹⁶ and the present Rietveld refinement.

STable 1. SPS Conditions Used to Densify the Four Polycrystalline Samples.

Compositions	Heating time	Heating temperature	Remaining time	Cooling time	Pressure at all steps
InSiTe ₃	2h30 (Step by Step)	773 K		60 min	28 MPa
Cr ₂ Si ₂ Te ₆	2h (Step by Step)		30 min		
In ₂ Ge ₂ Te ₆	45 min	710 K		45 min	64 MPa
Cr ₂ Ge ₂ Te ₆		823 K			

STable 2. Details on the Structure Refinement of Polycrystalline $\text{Cr}_2\text{Ge}_2\text{Te}_6$ and Atomic Coordinates (x,y,z), Site Occupation Factors, Isotropic Displacement Parameters (\AA^2) and their Estimated Standard Deviations Obtained from the Rietveld Refinement of $\text{Cr}_2\text{Ge}_2\text{Te}_6$.

Physical, Crystallographic and Analytic data							
compound	$\text{Cr}_2\text{Ge}_2\text{Te}_6$						
diffractometer radiation (\AA)	$\text{CuK}\alpha, \beta = 1.540600 \text{ and } 1.544400$						
2 θ range (deg), no. of points	5 – 120, 8758						
step size (deg)	0.013130						
no. of background points	93						
profile function	Thompson-Cox-Hastings pseudo-Voigt						
no. of refined parameters	16						
space group	$R\bar{3}$						
unit-cell parameters (\AA)	a = b	6.82869(9)					
	c =	20.5796(3)					
cell volume (\AA^3)	831.08(2)						
reliability factors	R_F (%)		7.83				
	R_B (%)		6.06				
	R_{WP} (%)		4.08				
	χ^2		2.43				
Refined coordinates, Atomic Displacement Parameters and their Estimated Standard Deviations from Rietveld Refinement							
atom	Wyckoff position	occ	x	y	z	U_{iso} (\AA^2)	
Cr	6c	1	0	0	0.3283(5)	0.054(3)	
Ge	6c	1	0	0	0.0612(3)	0.076(3)	
Te	18f	1	0.0025(7)	0.3534(3)	0.08442(1)	0.049(0)	

CAPTIONS:

SVid:

SVid1. X-ray diffraction evolution in temperature of the reflection intensities corresponding to InSiTe_3 , In_2Te_3 and Si_2Te_3 , resulting from the incongruent melting of the InSiTe_3 compound